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ATTY. DOCKET NO. U.S. PATENT 2038-310 INFORMATION DISCLOSURE APPLICATION NO. 10/730,260 CITATION IN AN APPLICANT APPLICATION Toshifumi OTSUBO FILING DATE GROUP (PTO-1449) December 9, 2003 3763 DOCUMENTS **EXAMINER'S** FILING INITIALS PATENT NO. DATE NAME **CLASS SUBCLASS** DATE 5171239 12-1992 Igaue et al. MW 5415649 05-1995 Watanabe et al. 6923797 08-2005 Shinohara et al. 5575783 11-1996 Clear et al. 5745922 05-1998 Rajala et al. Serbiak et al. 5846232 12-1998 6049916 04-2000 Rajala et al. 6595976 07-2003 Jitoe et al. 04-2002 2002/0049421 Hayase et al. 6297424 10-2001 Olson et al. FOREIGNPATENINDOGUMENTS **EXAMINER'S** PATENT NO. COUNTRY CLASS **SUBCLASS** DATE INITIALS 0761194 08-1996 Europe X 0762293 08-1996 Europe X 1184012 03-2002 X Europe 1997-38134 02-1997 X Japan 11-299829 11-1999 X Japan 04-1997 09-099006 X Japan 2000-107225 04-2000  $\mathbf{X}$ Japan 2003-038556 02-2003 Japan X OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) **EXAMINER** DATE CONSIDERED

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